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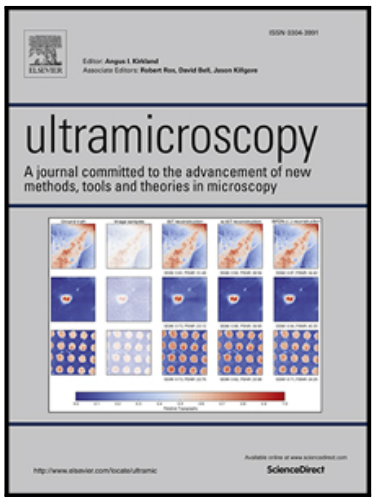

Electron-Beam Broadening in Amorphous Carbon Films in Low-Energy Scanning Transmission Electron Microscopy

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Highlights

- Electron beam broadening in low-energy scanning transmission electron microscopy
- Measurement based on multi-segmented STEM detector
- Results for thin amorphous carbon film with known thicknesses
- Quantitative description of experimental data with analytical model from literature

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